# PU7456

## Silicon N-Channel Power F-MOS FET (with built-in zener diode)

### Features

- High avalanche energy capacity
- High electrostatic breakdown voltage
- No secondary breakdown
- High breakdown voltage, large allowable power dissipation
- Allowing Low-voltage drive

### ■ Applications

- Contactless relay
- Diving circuit for a solenoid
- Driving circuit for a motor
- Control equipment
- Switching power supply

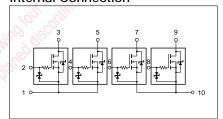
### ■ Absolute Maximum Ratings $(T_C = 25^{\circ}C)$

Parameter		Symbol	Ratings	Unit	
Drain to Source breakdown voltage		V <sub>DSS</sub>	35 ± 10	V	
Gate to Source voltage		V <sub>GSS</sub>	±20	V	
Drain current	DC	$I_D$	±6	A	
	Pulse	I <sub>DP</sub>	±12	A	
Avalanche energy	Non repetition	EAS*	200	mJ	
capacity	Repetition	EAR	8	mJ	
Allowable power	$T_C = 25^{\circ}C$	D	15	w	
dissipation	Ta = 25°C	$P_{\rm D}$	3.5		
Channel temperature		$T_{ch}$	150	°C	
Storage temperature		T <sub>stg</sub>	-55 to +150	°C/JO	

<sup>\*</sup> L = 11.2mH,  $I_L = 6$ A,  $V_{DD} = 50$ V, 1 pulse

# Unit: mm 25.3±0.2 4.0±0.2 0.8±0.25 1.0±0.25 2.5±0.15 4.0±0.25 0.5±0.15 G: Gate D: Drain S: Source 10-Lead Plastic SIL Package

### **Internal Connection**

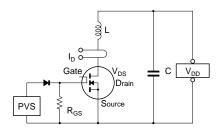


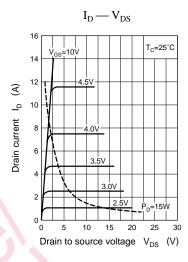
### ■ Electrical Characteristics (T<sub>C</sub> = 25°C)

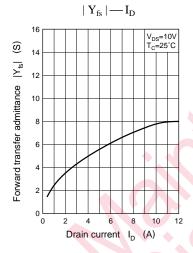
Parameter	Symbol	Conditions	min	typ	max	Unit
Drain to Source cut-off current	$I_{DSS}$	$V_{DS} = 20V, V_{GS} = 0$			10	μA
Gate to Source leakage current	I <sub>GSS</sub>	$V_{GS} = \pm 20V, V_{DS} = 0$			±1	μA
Drain to Source breakdown voltage	V <sub>DSS</sub>	$I_D = 1$ mA, $V_{GS} = 0$	25		45	V
Gate threshold voltage	V <sub>th</sub>	$V_{DS} = 25V$ , $I_D = 1mA$	1		2.5	V
Drain to Source ON-resistance	R <sub>DS(on)1</sub>	$V_{GS} = 10V, I_D = 3A$		110	140	mΩ
	R <sub>DS(on)2</sub>	$V_{GS} = 4V, I_D = 3A$		160	220	mΩ
Forward transfer admittance	Y <sub>fs</sub>	$V_{DS} = 25V, I_{D} = 3A$	3	5.5		S
Diode forward voltage	V <sub>DSF</sub>	$I_{DR} = 6A, V_{GS} = 0$			-1.7	V
Input capacitance (Common Source)	C <sub>iss</sub>			40		pF
Output capacitance (Common Source)	Coss	$V_{DS} = 10V, V_{GS} = 0, f = 1MHz$		300		pF
Reverse transfer capacitance (Common Source)	C <sub>rss</sub>			20		pF
Turn-on time	t <sub>on</sub>	$V_{GS} = 10V, I_D = 3A$		1		μs
Fall time	$t_{\rm f}$			2		μs
Turn-off time (delay time)	$t_{d(off)}$	$V_{DD} = 30V, R_L = 10\Omega$		1		μs

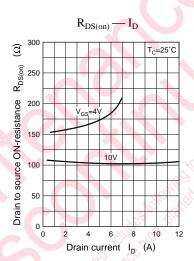
Panasonic 1

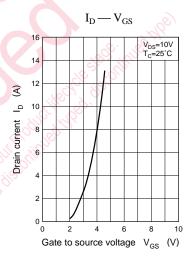
Avalanche energy capacity test circuit

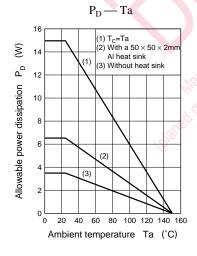


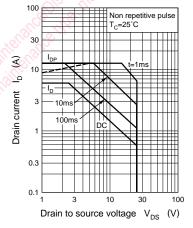




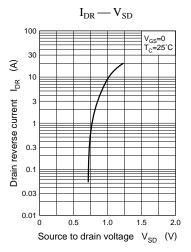








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